BTA330B-800BT

3Q Hi-Com Triac

Rev.01 - 16 October 2019 Product data sheet

1. General description

Planar passivated high commutation three quadrant triac in a TO263 (D^2PAK) surface mountable plastic package intended for use in circuits where high static and dynamic dV/dt and high dI_T/dt can occur. This triac will commutate the full RMS current at the maximum rated junction temperature ($T_{j(max)}$ = 150 °C) without the aid of a snubber. It is used in applications where high junction operating temperature capability is required.

2. Features and benefits

- 3Q technology for improved noise immunity
- High commutation capability with maximum false trigger immunity
- High junction operating temperature capability ($T_{j(max)}$ = 150 °C)
- High voltage capability
- High current capability
- Less sensitive gate for highest noise immunity
- Triggering in three quadrants only
- Very high immunity to false turn-on by dV/dt and fast transients
- Surface mountable plastic package
- Package is RoHS compliant

3. Applications

- Heating controls
- High power motor control
- High power switching
- Applications subject to high temperature ($T_{j(max)}$ = 150 °C)

4. Quick reference data

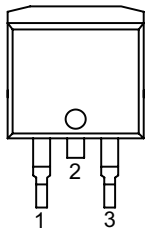
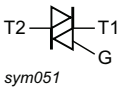
Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
V_{DRM}	repetitive peak off-state voltage			-	-	800	V
$I_{T(RMS)}$	RMS on-state current	full sine wave; $T_{mb} \leq 120$ °C; Fig. 1; Fig. 2; Fig. 3		-	-	30	A
I_{TSM}	non-repetitive peak on-state current	full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig. 4; Fig. 5		-	-	270	A
		full sine wave; $T_{j(init)}$ = 25 °C; t_p = 16.7 ms		-	-	297	A
T_j	junction temperature			-	-	150	°C
Static characteristics							
I_{GT}	gate trigger current	V_D = 12 V; I_T = 0.1 A; T2+ G+; T_j = 25 °C; Fig. 7		-	-	50	mA

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
		V_D = 12 V; I_T = 0.1 A; T2+ G-; T_j = 25 °C; Fig. 7		-	-	50	mA
		V_D = 12 V; I_T = 0.1 A; T2- G-; T_j = 25 °C; Fig. 7		-	-	50	mA
I_H	holding current	V_D = 12 V; T_j = 25 °C; Fig. 9		-	-	75	mA
V_T	on-state voltage	I_T = 42 A; T_j = 25 °C; Fig. 10		-	1.2	1.5	V
Dynamic characteristics							
dV_D/dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		4000	-	-	V/µs
		V_{DM} = 536 V; T_j = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		2000	-	-	V/µs
dI_{com}/dt	rate of change of commutating current	V_D = 400 V; T_j = 125 °C; $I_{T(RMS)}$ = 30 A; dV_{com}/dt = 20 V/µs; (snubberless condition); gate open circuit		20	-	-	A/ms
		V_D = 400 V; T_j = 150 °C; $I_{T(RMS)}$ = 30 A; dV_{com}/dt = 20 V/µs; (snubberless condition); gate open circuit		15	-	-	A/ms

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T1	main terminal 1		
2	T2	main terminal 2		
3	G	gate		
mb	T2	mounting base; main terminal 2		

6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
BTA330B-800BT	TO263	BTA330B-800BTJ	Reel	800	TO263E	26-May-2017

7. Marking

Table 4. Marking codes

Type number	Marking codes
BTA330B-800BT	BTA330B-800BT

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8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage			-	800	V
$I_{T(RMS)}$	RMS on-state current	full sine wave; $T_{mb} \leq 120$ °C; Fig. 1; Fig. 2; Fig. 3		-	30	A
I_{TSM}	non-repetitive peak on-state current	full sine wave; $T_{j(init)} = 25$ °C; $t_p = 20$ ms; Fig. 4; Fig. 5		-	270	A
		full sine wave; $T_{j(init)} = 25$ °C; $t_p = 16.7$ ms		-	297	A
I^2t	I^2t for fusing	$t_P = 10$ ms; sine wave pulse		-	364.5	A^2s
dI_T/dt	rate of rise of on-state current	$I_G = 70$ mA		-	100	A/µs
I_{GM}	peak gate current			-	2	A
P_{GM}	peak gate power			-	5	W
$P_{G(AV)}$	average gate power	over any 20 ms period		-	0.5	W
T_{stg}	storage temperature			-40	150	°C
T_j	junction temperature			-	150	°C

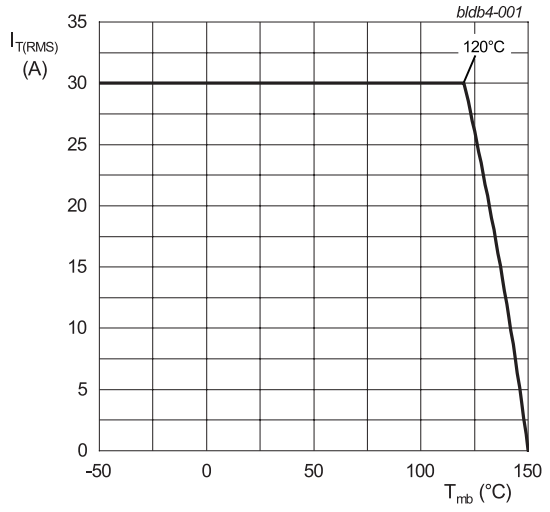
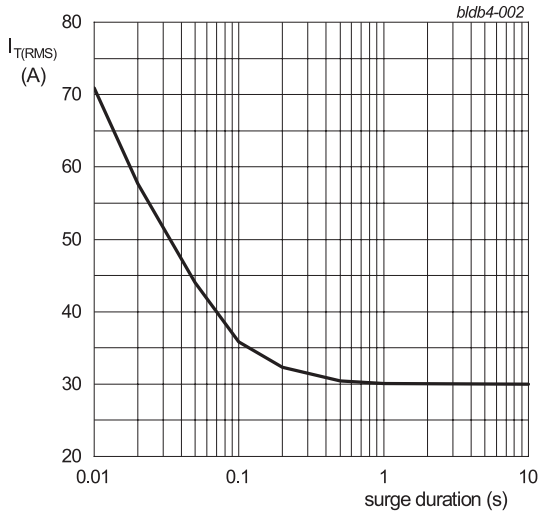


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values

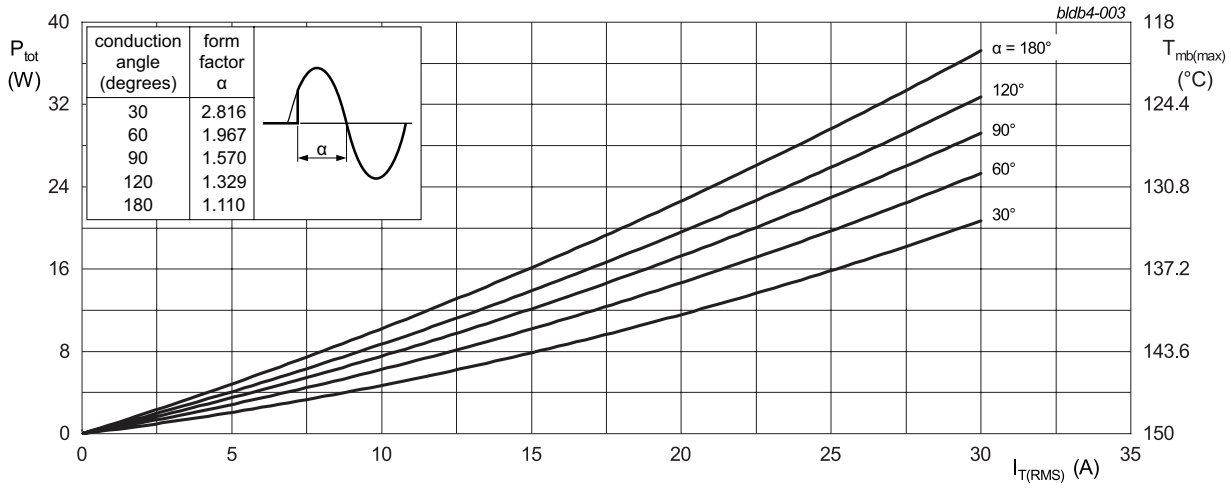


f = 50 Hz; T_{mb} = 120 °C

Fig. 2. RMS on-state current as a function of surge duration; maximum values

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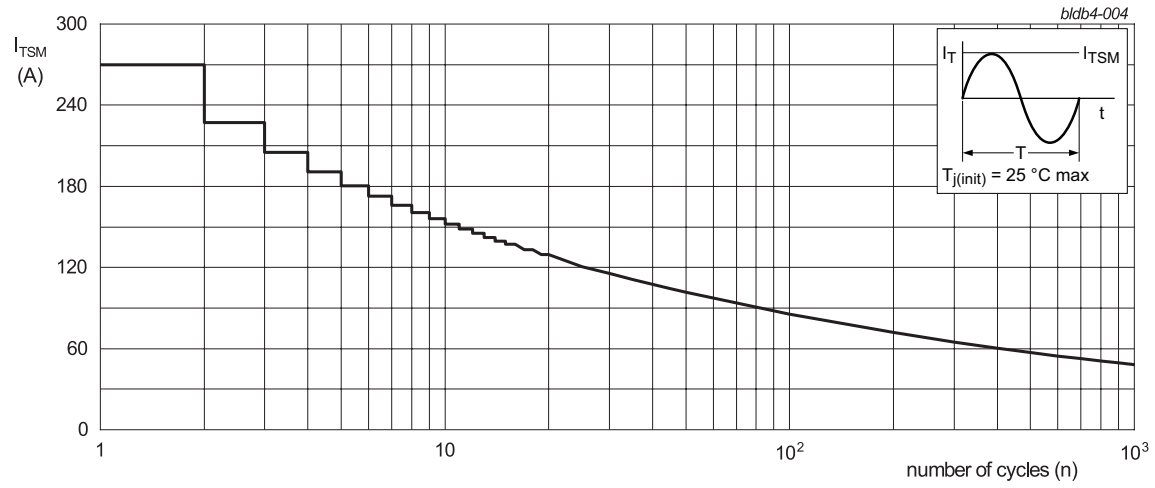
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α = conduction angle

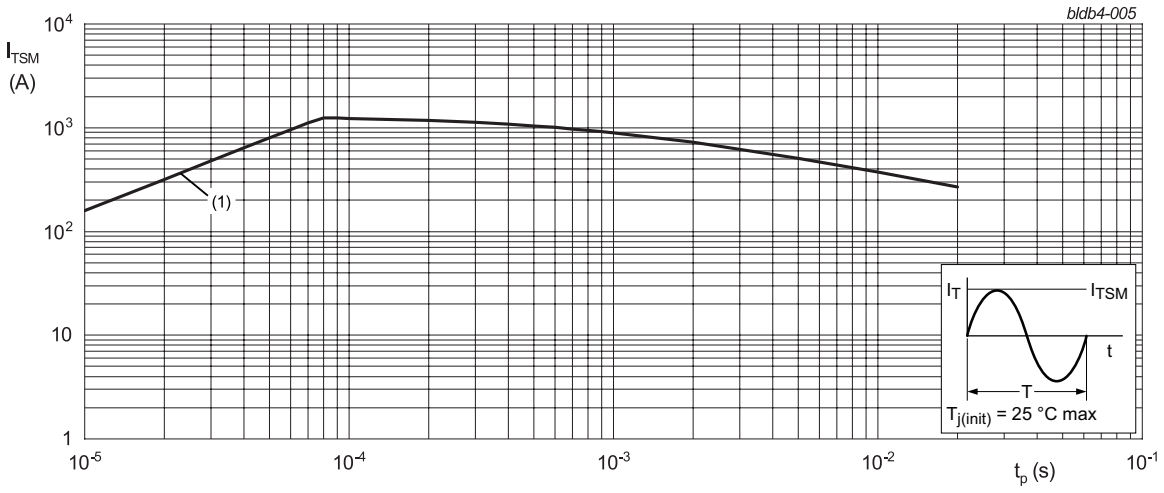
a = form factor = $I_{T(RMS)}$ / $I_{T(AV)}$

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values



f = 50 Hz

Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



t_p ≤ 20 ms

(1) dI_T/dt limit

Fig. 5. Non-repetitive peak on-state current as a function of pulse duration; maximum values

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9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	full cycle; Fig 6		-	-	0.8	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	printed circuit board mounted; minimum footprint		-	55	-	K/W

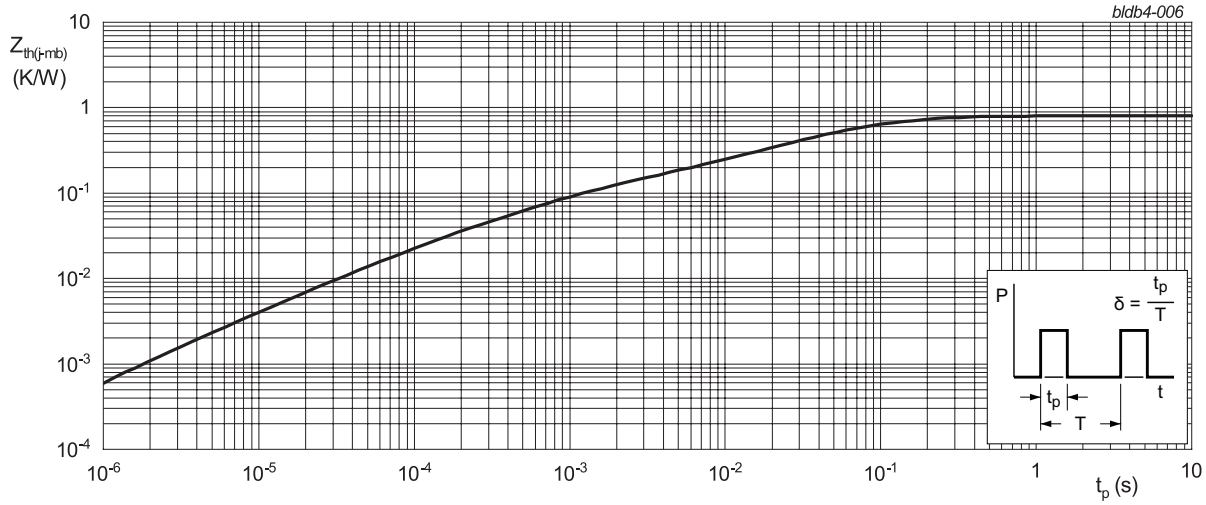


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse duration

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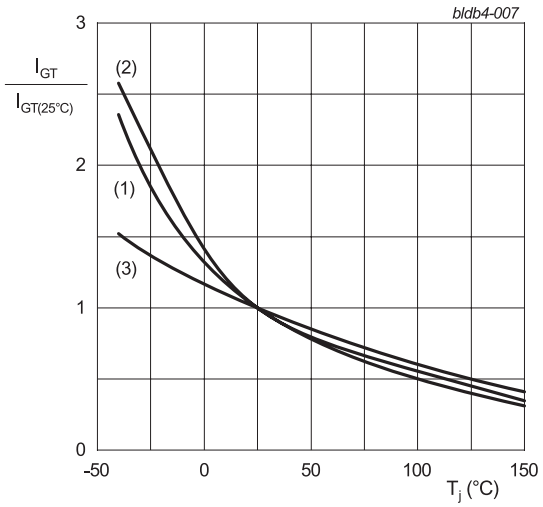
10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
Static characteristics							
I_{GT}	gate trigger current	V_D = 12 V; I_T = 0.1 A; T2+ G+; T_j = 25 °C; Fig. 7		-	-	50	mA
		V_D = 12 V; I_T = 0.1 A; T2+ G-; T_j = 25 °C; Fig. 7		-	-	50	mA
		V_D = 12 V; I_T = 0.1 A; T2- G-; T_j = 25 °C; Fig. 7		-	-	50	mA
I_L	latching current	V_D = 12 V; I_G = 0.1 A; T2+ G+; T_j = 25 °C; Fig. 8		-	-	80	mA
		V_D = 12 V; I_G = 0.1 A; T2+ G-; T_j = 25 °C; Fig. 8		-	-	100	mA
		V_D = 12 V; I_G = 0.1 A; T2- G-; T_j = 25 °C; Fig. 8		-	-	80	mA
I_H	holding current	V_D = 12 V; T_j = 25 °C; Fig. 9		-	-	75	mA
V_T	on-state voltage	I_T = 42 A; T_j = 25 °C; Fig. 10		-	1.2	1.5	V
V_{GT}	gate trigger voltage	V_D = 12 V; I_T = 0.1 A;T_j = 25 °C; Fig. 11		-	0.9	1.3	V
		V_D = 400 V; I_T = 0.1 A;T_j = 150 °C		0.2	0.45	-	V
I_D	off-state current	V_D = 800 V; T_j = 25 °C		-	-	10	µA
		V_D = 800 V; T_j = 125 °C		-	0.4	2	mA
Dynamic characteristics							
dV_D/dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		4000	-	-	V/µs
		V_{DM} = 536 V; T_j = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		2000	-	-	V/µs
dI_{com}/dt	rate of change of commutating current	V_D = 400 V; T_j = 125 °C; $I_{T(RMS)}$ = 30 A; dV_{com}/dt = 20 V/µs; (snubberless condition); gate open circuit		20	-	-	A/ms
		V_D = 400 V; T_j = 150 °C; $I_{T(RMS)}$ = 30 A; dV_{com}/dt = 20 V/µs; (snubberless condition); gate open circuit		15	-	-	A/ms

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(1) T2- G-
(2) T2+ G-
(3) T2+ G+

Fig. 7. Normalized gate trigger current as a function of junction temperature

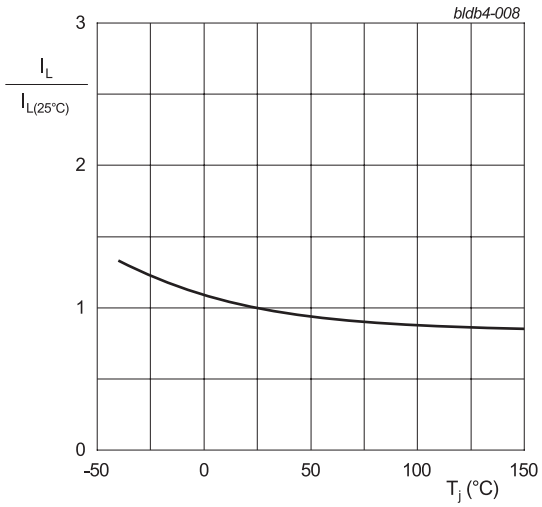


Fig. 8. Normalized latching current as a function of junction temperature

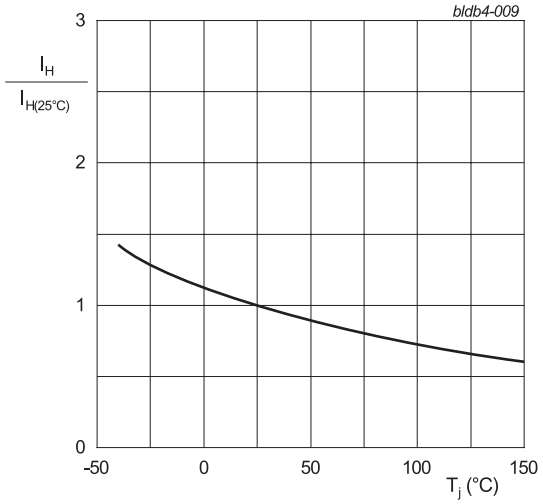
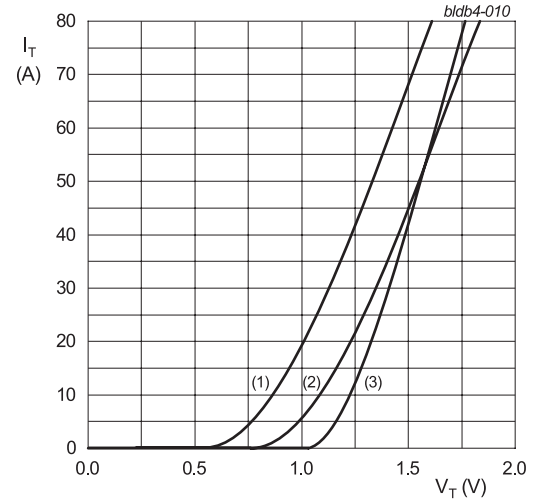


Fig. 9. Normalized holding current as a function of junction temperature



V_o = 1.011 V; R_s = 0.0110 Ω
(1) T_j = 150 °C; typical values
(2) T_j = 150 °C; maximum values
(3) T_j = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

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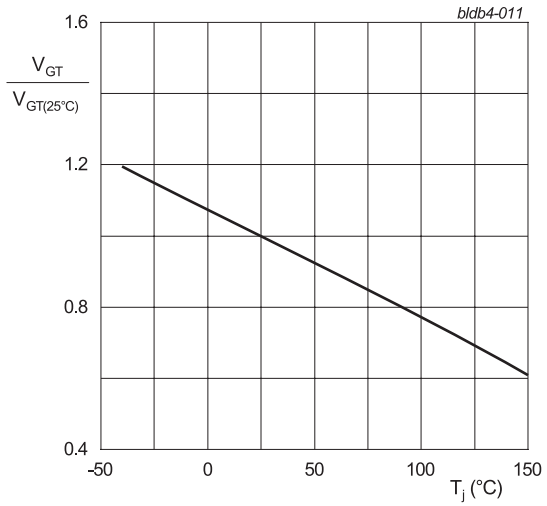


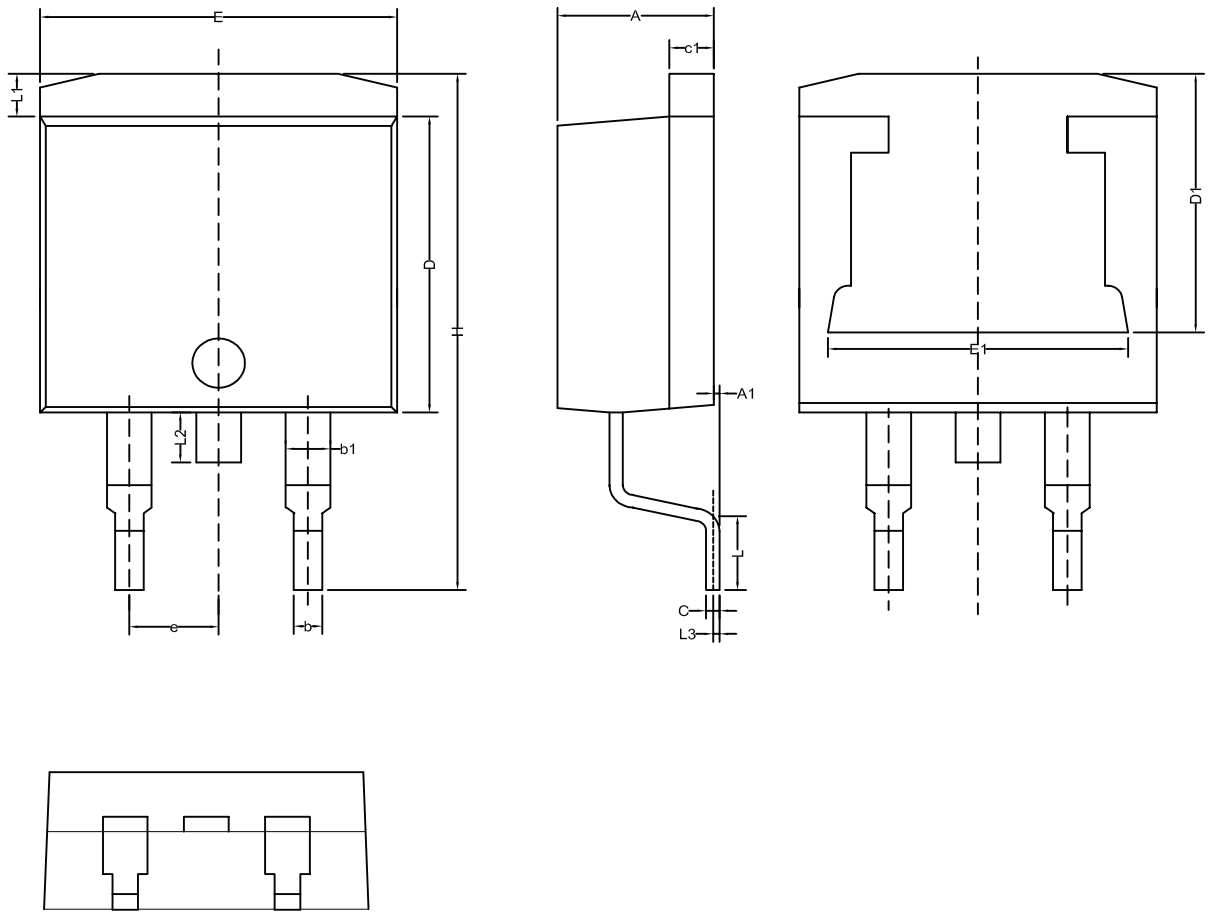
Fig. 11. Normalized gate trigger voltage as a function of junction temperature

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11. Package outline

Plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped) TO263



Unit		A	A1	b	b1	c	c1	D	D1	E	E1	e	H	L	L1	L2	L3
MM	min	4.35	0.00	0.69	1.14	0.38	1.14	8.50	7.50	10.00	8.25	2.54 (BSC)	14.60	2.50	1.00	1.27	0.25 (BSC)
	max	4.75	0.15	0.99	1.73	0.61	1.40	9.02	8.00	10.40	8.80		15.60	2.79	1.65	1.78	

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